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07/973,931 filed November 10, 1992, Patent No. 5,302,891,
which is a continuation of application serial no. 07/709,858
filed June 4, 1991, abandoned.

On page 2,
line 11, delete "being";
line 18, after "limited" add --over--.

On page 4,
line 2, change "exhibits" to --exhibit--.

On page 5,
line 30, delete "the" second occurrence.

On page 6,
line 27, after "includes" add --a--.

On page 8,
line 3, delete the comma.

On page 8,
line 10, delete "and the die 21, and which" and
substitute --and--;
line 11, after "plate" add --13--;
line 14, change "21" to --17--.

On page 9,
line 10, change "polyamide" to --polyimide--;
line 20 change, "an other" to --another--.

In the Claims

Please cancel claims 1-33.

34. (added) A test fixture for testing a semiconductor
die comprising:
a first plate for receiving the die;

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